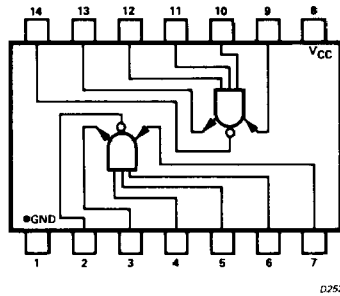


NAND BUFFER DRIVER
SP352 A Dual 3-Input Expandable
(Open Collector)

PIN CONFIGURATION



SP352A

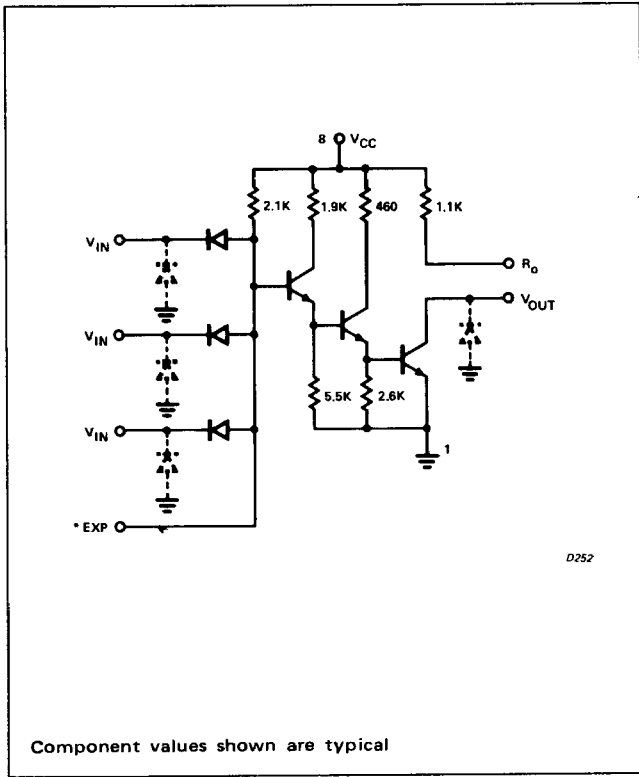
ELECTRICAL CHARACTERISTICS (Notes 1, 2, 3, 5 and 7)

Standard Conditions: $V_{CC} = 5.0V$, $T_A =$ Operating Temp. Range (Unless Noted)

CHARACTERISTIC	TEST CONDITIONS	MIN.	TYP.	MAX.	UNITS
Noise Immunity for "1" for "0"	See Note 6 See Note 6	N.A. 300	N.A. 600		mV
Output "1" Level Leakage	$V_{in} = 0.9V$, $V_{out} = 5.0V$		40	100	μA
"0" Level Voltage	$I_{out} = 45mA$, $V_{in} = 2.7V$ $I_{out} = 27mA$, $V_{in} = 2.1V$			0.6 0.4	V V
Input Current input high	$V_{in} = 5.0V$		5	25	μA
input low	$V_{in} = 0.6V$			-2.5	mA
input low (expander)	$V_{in} = 1.1V$			-2.5	mA
Power Supply Current output high	$V_{in} = 0V$, $T_A = 25^\circ C$			2.8	mA/gate
output low	$V_{in} = 4.0V$, $T_A = 25^\circ C$			16.7	mA/gate
Turn on Delay	See Test Figure 1, Output to R_O connected $T_A = 25^\circ C$			60	ns
Turn off Delay	See Test Figure 1, Output to R_O connected $T_A = 25^\circ C$			90	ns
Fan-out -To sink loads (2.5mA/load)				18	
-To source loads (180 μA /load)				N.A.	

Typical Values are for $T_A = 25^\circ C$. See Page 3 for Notes.

SCHEMATIC DIAGRAM



TEST CIRCUIT AND WAVEFORM

